| DCN Namely | | | | 700044040004 | | | | | | - | 201 0 | | _ | 10 2020 | |
|---|--------------------|------------------|---|---------------|----|------|--------------------------------|--------------------|-----------------------|----------------|------------------------------|---------------------|------|------------|------|
| PCN Numb | | oer: | 20 | 20201104000.1 | | | | | | P | CN D | ate: | Dec. | . 18, 2020 | |
| Title | : | _ | sembly Material set for Selected Device(s) | | | | | | | | | | | | |
| Customer | | Contact: | PCN | CN Manager | | | Dep | t: | | Quality | Ser | vices | S | | |
| Proposed 1 st Ship Date: | | e: | Mar. 18, 2021 | | | | Estimated Sample Availability: | | | | e provided at ple request | | | | |
| Char | nge Ty | | | | | | | | | | | | | | |
| Assembly Site | | | | | | | Desi | Design | | | | Wafer Bump Site | | | Site |
| Assembly Process | | | | | | | Data Sheet | | | | Wafer Bump Material | | | Material | |
| | | nbly Materials | | | | | | Part number change | | | Wafer Bump Process | | | | |
| | | anical Specifica | | | | | Test Site | | | Wafer Fab Site | | | | | |
| | Packir | ng/Shipping/La | abelin | g | | | Test | Proce | ess | | Ļ | Wafer Fab Materials | | | |
| | | | | | | | | | | | | Wafer Fab Process | | | |
| | | | | | | P | CN E | Deta | ils | | | | | | |
| Desc | criptio | n of Change | | | | | | | | | | | | | |
| Texas Instruments is pleased to announce the qualification of new assembly material for devices listed in "Product affected" section below. Devices will remain in current assembly facility and piece part changes as follows: | | | | | | | | | | | | | | | |
| Material | | | Current | | | rent | | Proposed | | | | | | | |
| Lead frame thickness | | ess | | 10 mils | | | nils | 10mi | | nils, (| ls, 6mils | | | | |
| Mount compound | | | | | | 4042 | 2500 | | | 4: | 1478 | 358 | | | |
| Mold compound | | | | 4205694 | | | 694 | | 4211880 | | 880 | | | | |
| Reas | Reason for Change: | | | | | | | | | | | | | | |
| Continuity of supply. | | | | | | | | | | | | | | | |
| Anticipated impact on Fit, Form, Function, Quality or Reliability (positive / negative): | | | | | | | | gative): | | | | | | | |
| None | None. | | | | | | | | | | | | | | |
| Anticipated impact on Material Declaration | | | | | | | | | | | | | | | |
| No Impact to the Material Declaration | | n | Material Declarations or Product Content reports are driver from production data and will be available following the production release. Upon production release the revised reports can be obtained from the <u>TI ECO website</u> . | | | | | | ring the e revised | | | | | | |
| Changes to product identification resulting from this PCN: | | | | | | | | | | | | | | | |
| None | <u> </u> | | | | | | | | | | | | | | |
| Prod | luct A | ffected: | | | | | | | | | | | | | |
| CD74HC154M | | | CD7 | 4HC15 | 4M | 960 | | CD7 | 4H0 | C154MG4 | | | CDC2 | 04DV | V |

Qualification Report

Approve Date 12-May-2016

Qualification Results

Data Displayed as: Number of lots / Total sample size / Total failed

| Туре | Test Name / Condition | Duration | Qual Device: ADS1213U | Qual Device: ADS820U | Qual Device: ADS8504IBD W | Qual Device: MSP430F123I DWR | Qual Device: SN65LBC170 DW |
|------|---|---|--------------------------|-------------------------|---------------------------------|------------------------------------|----------------------------------|
| AC | Autoclave 121C | 96 Hours | 1/77/0 | - | 1/77/0 | 1/77/0 | 1/77/0 |
| ED | Electrical Characterization, side by side | Per datasheet parameters | Pass | Pass | Pass | - | Pass |
| HAST | Biased HAST, 130C/85%RH | 192 Hours | - | - | - | - | - |
| HAST | Biased HAST, 130C/85%RH | 96 Hours | - | - | - | - | - |
| HTSL | High Temp Storage Bake 170C | 420 Hours | 1/77/0 | - | 1/77/0 | 1/77/0 | 1/77/0 |
| MQ | Manufacturability (Assembly) | (per mfg. Site specificatio n) | Pass | Pass | Pass | Pass | Pass |
| TC | Temperature Cycle, - 65/150C | 500 CVCIES | | 3/231/0 | 1/77/0 | 1/77/0 | 1/77/0 |

| Туре | Test Name / Condition | Duration | Qual Device: SN65LBC17 0DW_ SSTN | Qual Device: SN74LVC541 ADW | Qual Device: SN74LVC541 ADW_SSTN | QBS Package Reference: TL494IDR | QBS Package Reference: ULQ2003AQD RQ1_STDLF |
|------|---|--------------------------------|---|-----------------------------------|--|---------------------------------------|--|
| AC | Autoclave 121C | 96 Hours | 3/231/0 | 3/231/0 | 3/231/0 | - | 3/231/0 |
| ED | Electrical Characterization, side by side | Per datasheet parameters | Pass | Pass | Pass | - | - |
| HAST | Biased HAST, 130C/85%RH | 192 Hours | - | - | - | 3/231/0 | 3/217/0 |
| HAST | Biased HAST, 130C/85%RH | 96 Hours | - | - | - | 3/231/0 | 3/231/0 |
| HTSL | High Temp Storage Bake 170C | 420 Hours | 3/231/0 | 3/231/0 | 3/231/0 | - | - |
| MQ | Manufacturability (Assembly) | (per mfg. Site specification) | Pass | Pass | Pass | - | - |
| TC | Temperature Cycle, - 500 Cycles | | 3/231/0 | 3/231/0 | 3/231/0 | - | 3/231/0 |

- QBS: Qual By Similarity
- Qual Devices qualified at LEVEL1-260C: SN65LBC170DW, SN74LVC541ADW, MSP430F123IDWR, TL494IDR, ULQ200AQDRQ1
- Qual Devices qualified at LEVEL2-260C: ADS1213U, ADS8504IBDW, ADS820U
- Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable
- The following are equivalent HTOL options based on an activation energy of 0.7eV: 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours
- The following are equivalent HTSL options based on an activation energy of 0.7eV: 150C/1k Hours, and 170C/420 Hours
- The following are equivalent Temp Cycle options per JESD47 : -55C/125C/700 Cycles and -65C/150C/500 Cycles Quality and Environmental data is available at TI's external Web site: http://www.ti.com/ Green/Pb-free Status:

Qualified Pb-Free(SMT) and Green

Qualification Report

Approve Date 07-Aug-2017

Qualification Results

Data Displayed as: Number of lots / Total sample size / Total failed

| Туре | Test Name / Condition Duration | | Qual Device: SN74HCT573DWR _RLF_AU | Qual Device: SN74HCT573DWR _RLF_CU | Qual Device: SN74LVC244ADWR _RLF_AU | Qual Device: SN74LVC244ADWR _RLF_CU |
|------|-------------------------------------|-------------------------------------|--|--|---|---|
| LI | Lead Fatigue Leads | | 3/66/0 | 3/66/0 | 1/66/0 | 3/66/0 |
| LI | Lead Pull to Destruction | Leads | 3/66/0 | 3/66/0 | 1/66/0 | 3/66/0 |
| MQ | Manufacturability (Assembly) | (per mfg. Site specification) | Pass | Pass | Pass | Pass |
| PD | Physical Dimensions | | 3/15/0 | 3/15/0 | 3/15/0 | 3/15/0 |
| SD | Solderability | 8 Hours Steam Age | 3/66/0 | 3/66/0 | 3/66/0 | 3/66/0 |
| TC | Temperature Cycle, - 65C/150C | 500 Cycles | 3/231/0 | 3/231/0 | 3/231/0 | 3/231/0 |
| WBP | Bond Pull Wires | | 3/228/0 | 3/228/0 | 3/228/0 | 3/228/0 |
| WBP | Bond Strength | Wires | 3/228/0 | 3/228/0 | 3/228/0 | 3/228/0 |

- Qual Devices qualified at LEVEL1-260C: SN74HCT573DWR_RLF_AU, SN74HCT573DWR_RLF_CU, SN74LVC244ADWR_RLF_CU, SN74LVC244ADWR_RLF_AU
- Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable
- The following are equivalent HTOL options based on an activation energy of 0.7eV : 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours
- The following are equivalent HTSL options based on an activation energy of 0.7eV: 150C/1k Hours, and 170C/420 Hours
- The following are equivalent Temp Cycle options per JESD47 : -55C/125C/700 Cycles and -65C/150C/500 Cycles Quality and Environmental data is available at Tl's external Web site: http://www.ti.com/

Green/Pb-free Status:

Qualified Pb-Free(SMT) and Green

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